

David Root - Biography

Dr. David E. Root received B.S. degrees in physics and mathematics, and, in 1986, the Ph.D. degree in physics, all from MIT. He joined Hewlett-Packard Company (now Agilent Technologies) in 1985 where he has held both technical and management positions. He is presently Principal Research Scientist and Modeling Architect at Agilent Technologies' Worldwide Process and Technology Centers in Santa Rosa, CA. His current responsibilities include nonlinear behavioral and device modeling, large-signal simulation, and nonlinear measurements for new technical capabilities and business opportunities for Agilent. David was elected IEEE Fellow in 2002 "for contributions to nonlinear modeling of active semiconductor devices." He was 2006-2008 IEEE MTT-S Distinguished Microwave Lecturer. David received the 2007 IEEE ARFTG Technology Award "for contributions to nonlinear RF and microwave device measurement and behavioral modeling." Dr. Root was Visiting Scholar and Lecturer at the University of California, San Diego Fall, 2005. He co-edited the recent book, *Fundamentals of Nonlinear Behavioral Modeling for RF and Microwave Design*, Artech House, 2005. He has published about 100 technical journal articles, book chapters, international conference and workshop papers, and other technical papers. In 2008, David and collaborators received Agilent Technologies' Barnholt Award for the company's top innovation out of 1500 entries across all businesses for the Nonlinear Vector Network Analyzer and X-parameters. He is currently the Chair of IEEE MTT-1 Computer-Aided Design Technical Committee.